

Notice of Allowability

Application No.

10/662,830

Examiner

Ernest F. Karlsen

Applicant(s)

HOLLMAN, KENNETH F.

Art Unit

2829

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to the filing of September 15, 2003.
2. ☒ The allowed claim(s) is/are 1-22.
3. ☒ The drawings filed on 15 September 2003 are accepted by the Examiner.
4. ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) ☐ All b) ☐ Some* c) ☐ None of the:
 1. ☐ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

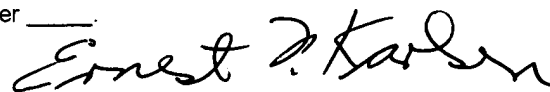
* Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

5. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
 6. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) ☐ hereto or 2) ☐ to Paper No./Mail Date _____.
 - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.
- Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
7. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

1. ☒ Notice of References Cited (PTO-892)
2. ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3. ☒ Information Disclosure Statements (PTO-1449 or PTO/SB/08),
Paper No./Mail Date 0903
4. ☐ Examiner's Comment Regarding Requirement for Deposit
of Biological Material
5. ☐ Notice of Informal Patent Application (PTO-152)
6. ☐ Interview Summary (PTO-413),
Paper No./Mail Date _____.
7. ☒ Examiner's Amendment/Comment
8. ☒ Examiner's Statement of Reasons for Allowance
9. ☐ Other _____



ERNEST KARLSEN
PRIMARY EXAMINER

Reasons for Allowance

No reference was found anticipating or a combination of references found making obvious a probe station system comprising a platform for positioning a microscope or a microscope, a support for a specimen, apparatus for acquiring an image identifying conductive path indicia of the surface of the specimen from the microscope, probe control apparatus for controlling a plurality of positionable probes, a vacuum chamber, feedthrough apparatus for conducting a signal to remotely control the probes, wherein the apparatus for acquiring an image controls the probe control apparatus using the acquired image to identify the electrically conductive terminals from the conductive path indicia of the surface of the specimen observed with the microscope. No reference was found anticipating or a combination of references found making obvious a method of analyzing an integrated circuit specimen comprising positioning a microscope for observing a specimen on a support, acquiring an image identifying conductive path indicia of the surface of the specimen from the microscope, remotely controlling a plurality of probes in a vacuum chamber in which a vacuum is generated, the chamber holding the microscope and the specimen and coupling signals via a feedthrough on the chamber for applying electrical test signals to the terminals of the specimen by remotely controlling the probes using the conductive path indicia of the surface of the specimen observed with the microscope.

Examiner's Amendment

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided

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by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

In the specification, page 1, line 4, before "which", --now U.S. Patent No. 6,621,282, -- has been inserted.

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Kasai et al and Todokoro are cited to show prior art where an electron beam microscope where probe tips contacting a semiconductor device under test are in the field of view of the electron beam microscope.

Claims 1-22 are allowed.

Any inquiry concerning this communication should be directed to Ernest F. Karlsen at telephone number 571-272-1961.

Ernest F. Karlsen

June 25, 2004

A handwritten signature in black ink, appearing to read "Ernest F. Karlsen", with a stylized, cursive script.

**ERNEST KARLSEN
PRIMARY EXAMINER**